

Notice of References Cited	Application/Control No. 10/812,734	Applicant(s)/Patent Under Reexamination SHUE ET AL.	
	Examiner Bradley K Smith	Art Unit 2824	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,472,231 B1	10-2002	Gabriel et al.	438/9
	B	US-6,387,805 B2	05-2002	Ding et al.	438/687
	C	US-6,693,356 B2	02-2004	Jiang et al.	257/767
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Adams et al. "Titanium-nitride self encapsulation of Cu and Ag films on silicon dioxide" (1997) Thin Solid Films pp. 448-454
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.